

Notice of References Cited	Application/Control No. 10/564,718		Applicant(s)/Patent Under Reexamination ANRAKU ET AL.	
	Examiner NED A. WALKER		Art Unit 3781	Page 1 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,499,568 A	03-1970	RIERA JOSE VINAS	215/276
*	B	US-4,019,646 A	04-1977	Imamura, Masanaga	215/329
*	C	US-4,094,429 A	06-1978	Urbain, Matthew C.	215/305
*	D	US-4,465,200 A	08-1984	Percarpio, Edward P.	215/247
*	E	US-4,569,457 A	02-1986	Hatakeyama et al.	215/364
*	F	US-4,697,717 A	10-1987	Grippi, Nicholas A.	215/354
*	G	US-4,813,578 A	03-1989	Gordon et al.	222/541.1
*	H	US-4,967,919 A	11-1990	Earhart, Stephen B.	215/247
*	I	US-5,275,299 A	01-1994	Konrad et al.	215/341
*	J	US-5,306,270 A	04-1994	Macartney et al.	604/415
*	K	US-5,361,921 A	11-1994	Burns, James A.	215/320
*	L	US-5,522,518 A	06-1996	Konrad et al.	215/247
*	M	US-5,819,964 A	10-1998	Grimard, Jean Pierre	215/249

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/564,718		Applicant(s)/Patent Under Reexamination ANRAKU ET AL.	
	Examiner NED A. WALKER		Art Unit 3781	Page 2 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,819,978 A	10-1998	Hlebovy, James C.	220/601
*	B	US-5,857,580 A	01-1999	Iidaka, Tsuguo	215/256
*	C	US-6,003,566 A	12-1999	Thibault et al.	141/25
*	D	US-6,189,580 B1	02-2001	Thibault et al.	141/25
*	E	US-6,213,994 B1	04-2001	Jansen et al.	604/415
*	F	US-6,378,576 B2	04-2002	Thibault et al.	141/329
*	G	US-6,378,714 B1	04-2002	Jansen et al.	215/249
*	H	US-6,382,442 B1	05-2002	Thibault et al.	215/249
*	I	US-6,602,206 B1	08-2003	Niermann et al.	600/573
*	J	US-6,626,309 B1	09-2003	Jansen et al.	215/249
*	K	US-6,681,946 B1	01-2004	Jansen et al.	215/249
*	L	US-2004/0099629 A1	05-2004	Whitley, Kenneth W.	215/276
*	M	US-6,806,094 B2	10-2004	Anderson et al.	436/180

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/564,718		Applicant(s)/Patent Under Reexamination ANRAKU ET AL.	
	Examiner NED A. WALKER		Art Unit 3781	Page 3 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0256348 A1	12-2004	Stevens et al.	215/262
*	B	US-6,945,417 B2	09-2005	Jansen et al.	215/249
*	C	US-7,097,057 B2	08-2006	Classens, Albert Louis	215/247
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.